

CLAIMS

Please amend the claims to read as indicated below.

1. (Currently amended) A capacitance measurement system having a test head comprising:
 - multiple input/output terminals connecting a device under test;
 - a source and measure ~~major~~-unit supplying voltage or current;
 - a capacitance measurement unit having an impedance measurement function; and
 - a switch matrix connecting said multiple input/output terminals, said source and measure ~~major~~-unit, and said capacitance measurement unit; andan external controller that is connected to said test head and controls a test head controller, wherein said test head controller controls said source and measure unit, said capacitance measurement unit, and said switch matrix.
2. (Cancelled)
3. (Original) The capacitance measurement system according to claim 1, wherein said test head comprises a calibration terminal of said capacitance measurement unit and an outside connection terminal of said switch matrix, and said capacitance measurement unit and said switch matrix are connected via said calibration terminal and said outside connection terminal.
4. (Original) The capacitance measurement system according to claim 1, wherein said capacitance measurement unit transmits an absolute value and phase of impedance of said device under test to said test head controller.
5. (Cancelled)

6. (Original) The capacitance measurement system according to claim 1, wherein said capacitance measurement unit transmits a value of a real part and an imaginary part of an impedance of said device under test to said test head controller.

7. (Currently amended) The capacitance measurement system according to claim 32, wherein said capacitance measurement unit transmits an absolute value and phase of impedance of said device under test to said test head controller.

8. (Cancelled)

9. (Currently amended) The capacitance measurement system according to claim 32, wherein said capacitance measurement unit transmits a value of a real part and an imaginary part of an impedance of said device under test to said test head controller.